Special Issue

Modelling, Simulation, Design, and Manufacturing of CMOS Integrated MEMS

Message from the Guest Editors

This Special Issue focuses on the modeling, simulation, design, and manufacture of CMOS-integrated MEMS sensors, but MEMS integrated in other standard microelectronics technologies will be also considered. Original research and review papers are welcome.
Topics include but are not limited to:

- Modeling, simulation, and integration of new physical, chemical or biological MEMS sensors in standard microelectronics technologies;
- Technological add-ons to standard microelectronics technologies for MEMS integration;
- Electronic design automation for MEMS design, co-simulation of MEMS with electronics, high-level modeling of MEMS;
- Integrated self-test and self-calibration of MEMS, industrial test procedures of CMOS MEMS.

Guest Editors

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Deadline for manuscript submissions

closed (31 December 2021)

Sensors

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Impact Factor 3.5
CiteScore 8.2
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mdpi.com/si/25619

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Message from the Editor-in-Chief

Sensors is a leading journal devoted to fast publication of the latest achievements of technological developments and scientific research in the huge area of physical, chemical and biochemical sensors, including remote sensing and sensor networks. Both experimental and theoretical papers are published, including all aspects of sensor design, technology, proof of concept and application. Sensors organizes Special Issues devoted to specific sensing areas and applications each year.

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